Application Serial No. 09/869,789 Amendment dated August 18, 2004 Reply to Final Office Action dated May 20, 2004

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-33 (canceled)

Claim 34 (currently amended): Raster probe microscope according to claim 30 A raster probe microscope for the examination of sample surfaces, comprising:

a raster probe;

a holding device for a sample with the sample surface to be examined;

an arrangement for moving the raster probe and/or the sample by which the probe and sample can be brought into contact so that they interact with one another in a given manner;

an arrangement for detecting the relative movement of the probe and sample;

an arrangement for controlling the movement of the raster probe and/or sample and for exciting a vertical first raster probe and/or sample oscillation and for exciting at least one of a vertical and horizontal second raster probe and/or sample oscillation; and

an arrangement for detecting at least one of a vertical and lateral deformation of the raster probe in a vertical first oscillation and at least one of a vertical and horizontal second oscillation;

the arrangement for detecting deformation recording two measuring signals characterizing the deformation of the raster probe in a vertical first oscillation and at least one of a vertical and horizontal second oscillation of the raster probe and/or sample, and characterized by periodic raster-probe and/or sample oscillations,

wherein the vertical oscillation of the raster probe and/or of the sample is additionally excited or modulated with a second frequency of at least 1 kHz and a second an amplitude of at least 0.1nm.

Claim 35 (new): Raster probe microscope according to claim 34, wherein the frequency ranges from 5 kHz to 1 MHz and the amplitude from 1 to 10 nm.

Claim 36 (canceled)

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Claim 37 (new): Raster probe microscope according to claim 34, wherein the frequency ranges from 10 to 100 kH and the amplitude from 1 to 30 nm.

Claims 38-54 (canceled)